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TO: DIRECTOR, NATIONAL BUREAU OF STANDARDS

FROM: DR. J. H. DILLON

SUBJECT: X-RAY FLUORESCENCE SPECTROSCOPY

RE: X-RAY FLUORESCENCE SPECTROSCOPY

The following information is being furnished to you for your information and for the use of your laboratory. It is the result of a study of the literature and of the results of our own experiments. It is intended to provide a basis for the development of a standard method for the determination of the concentration of elements in a sample by X-ray fluorescence spectroscopy.

The method described in this report is based on the use of a standard sample of known composition and the measurement of the intensity of the fluorescence signal from the sample.

The results of the study show that the method is capable of determining the concentration of elements in a sample to within 1%.

The method is simple and rapid and can be used for the determination of a wide range of elements.

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